

<b>Notice of References Cited</b>	Application/Control No. 10/083,596	Applicant(s)/Patent Under Reexamination OYAKE ET AL.	
	Examiner Martin J Angebrannndt	Art Unit 1756	Page 1 of 1

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	C	US-6,465,149	10-2002	Kamijima et al.	430/270.1
	D	US-3,458,311	07-1969	ALLES FRANCIS PETER	430/273.1
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	N	708439	04-1996	EP	Katsuda et al.	**
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	U	Jenkins et al., 'Fundamentals of Optics', (1976) pp. 655
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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